

# A vectorial solver for the reflection of semi-confined waves at slab waveguide discontinuities for non-perpendicular incidence

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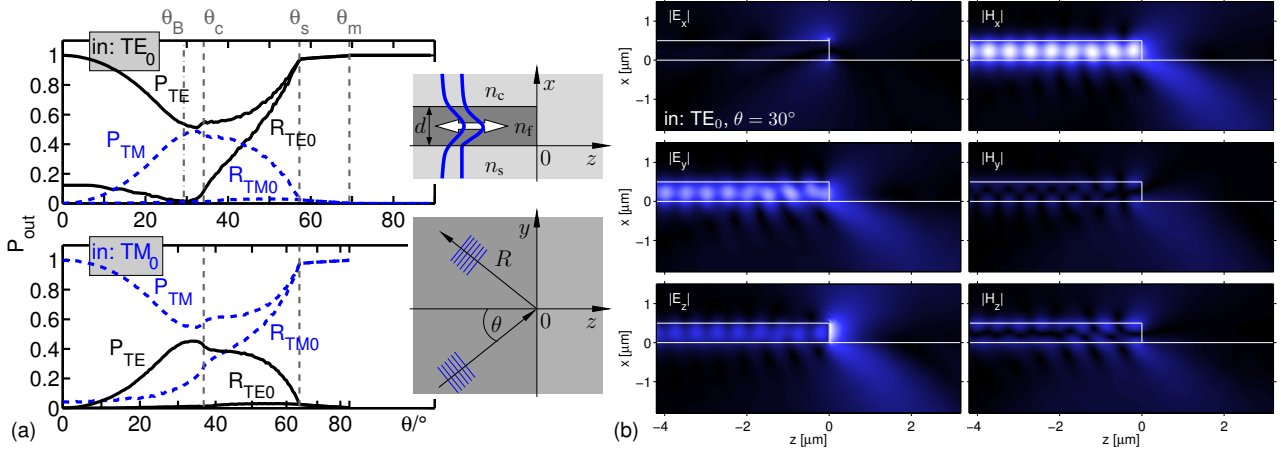
The non-normal incidence of thin-film guided, in-plane unguided optical waves on straight, possibly composite slab waveguide facets is considered. The quasi-analytical, vectorial solutions permit to inspect polarization properties of reflected and refracted guided waves, radiative losses, and full field details near the facet.

## Non-normal light incidence on a slab waveguide discontinuity

The effects of a straight transition between regions with different layering, or of a core facet, on thin-film guided, in-plane unguided light forms the basis for a series of classical integrated optical components. While scalar TE / TM Helmholtz equations apply for perpendicular incidence, for non-normal incidence one is led to a vectorial problem [1] that is formally identical to that for the modes of 3-D channel waveguides. Here, however, it needs to be solved as a parametrized, inhomogeneous system on a 2-D computational window with transparent-influx boundary conditions.

## Vectorial, quasi-analytical solutions by quadridirectional eigenmode propagation (QUEP)

As a step beyond the scalar approximation [1] and an older bidirectional approach [2], we report on a dedicated vectorial solver for — in principle — arbitrary rectangular cross section geometries, based on simultaneous expansions into slab modes along *two* orthogonal coordinate axes (QUEP, [3]). A review of general aspects (solver specifics, power balance, reciprocity, characteristic angles), will be followed by a discussion of solutions for different configurations, including the example below.



Reflection of semi-guided plane waves at a thin film facet. (a): reflected / outgoing power carried by the TE<sub>0</sub> / TM<sub>0</sub> modes ( $R_{TE0}$ ,  $R_{TM0}$ ) and by all TE / TM waves ( $P_{TE}$ ,  $P_{TM}$ ) for TE<sub>0</sub>- (top) or TM<sub>0</sub>-excitation (bottom), versus incidence angle  $\theta$ ; critical angles  $\theta_c$ ,  $\theta_s$ ,  $\theta_m$  for power being carried away by “cover”, “substrate”, and TM-fields; quasi-Brewster angle  $\tan \theta_B = n_c / n_{eff,TE0}$ . (b): e.m. components (absolute values) for TE<sub>0</sub>-excitation at  $\theta = 30^\circ$ . Parameters:  $n_s : n_f : n_c = 1.5 : 2.0 : 1.0$ ,  $d = 0.5 \mu\text{m}$ , vacuum wavelength  $\lambda = 1.55 \mu\text{m}$ .

## References

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- [3] M. Hammer. *Optics Communications*, 235(4–6):285–303, 2004.